

## Dual N-CH40V Fast Switching MOSFETs

### ❖ GENERAL DESCRIPTION

The AMS4204 is the high cell density trench N-ch MOSFETs, which provide excellent R<sub>DS(on)</sub> and gate charge for most of the synchronous buck converter applications.

The AMS4204 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

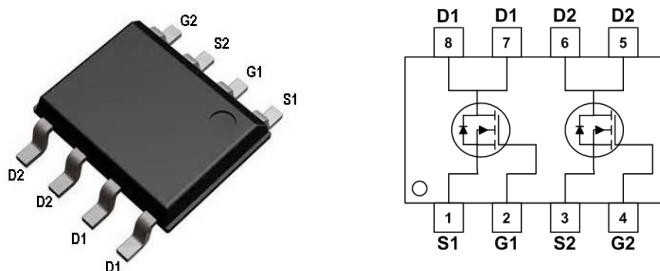
### ❖ FEATURES

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

### Product Summary

BVDSS	R <sub>DS(on)</sub>	I <sub>D</sub>
40V	15mΩ	7.5A

### SOP8 Pin configuration



❖ **ABSOLUTE MAXIMUM RATINGS**

Characteristics	Symbol	Rating	Units
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current, $V_{GS}$ @ -10V (Note 1)	$I_D@T_A=25^{\circ}C$	7.5	A
Continuous Drain Current, $V_{GS}$ @ -10V (Note 1)	$I_D@T_A=70^{\circ}C$	6	A
Pulsed Drain Current (Note 2)	$I_{DM}$	30	A
Single Pulse Avalanche Energy (Note 3)	EAS	69	mJ
Avalanche Current	$I_{AS}$	25	A
Total Power Dissipation (Note 4)	$P_D@T_A=25^{\circ}C$	1.5	W
Storage Temperature Range	$T_{STG}$	-55 to 150	$^{\circ}C$
Operating Junction Temperature Range	$T_J$	-55 to 150	$^{\circ}C$
Thermal Resistance Junction-Ambient (Steady State) (Note 1)	$R_{\theta JA}$	85	$^{\circ}C/W$
Thermal Resistance Junction-Case (Note 1)	$R_{\theta JC}$	36	$^{\circ}C/W$

Note 1: The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

Note 2: The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$

Note 3: The EAS data shows Max. rating. The test condition is  $V_{DD}=-25V$ ,  $V_{GS}=-10V$ ,  $L=0.1mH$ ,  $I_{AS}=-27.2A$

Note 4: The power dissipation is limited by 150 $^{\circ}C$  junction temperature

Note 5: The Min. value is 100% EAS tested guarantee.

Note 6: The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.

## ❖ ELECTRICAL CHARACTERISTICS

(T<sub>J</sub>=25 °C, unless otherwise noted)

Characteristics	Symbol	Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	40	-	-	V
BVDSS Temperature Coefficient	ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Reference to 25°C, I <sub>D</sub> =1mA	-	0.034	-	V/°C
Static Drain-Source On-Resistance (Note 2)	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V , I <sub>D</sub> =6A	-	12	15	mΩ
		V <sub>GS</sub> =4.5V , I <sub>D</sub> =3A	-	16	20	
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.0	1.5	2.5	V
V <sub>GS(th)</sub> Temperature Coefficient	ΔV <sub>GS(th)</sub>		-	-5.64	-	mV/°C
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =32V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C	-	-	1	uA
		V <sub>DS</sub> =32V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C	-	-	5	
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V	-	-	±100	nA
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> =5V , I <sub>D</sub> =6A	-	31	-	S
Gate Resistance	R <sub>g</sub>	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz	-	2.1	4.2	Ω
Total Gate Charge (4.5V)	Q <sub>g</sub>	V <sub>DS</sub> =20V , V <sub>GS</sub> =4.5V, I <sub>D</sub> =6A	-	10.7	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	3.3	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	4.2	-	
Turn-On Delay Time	T <sub>d(on)</sub>	V <sub>DD</sub> =12V , V <sub>GS</sub> =10V, R <sub>G</sub> =3.3Ω I <sub>D</sub> =6A	-	8.6	-	ns
Rise Time	T <sub>r</sub>		-	3.4	-	
Turn-Off Delay Time	T <sub>d(off)</sub>		-	25	-	
Fall Time	T <sub>f</sub>		-	2.2	-	
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V, f=1MHz	-	1314	-	pF
Output Capacitance	C <sub>oss</sub>		-	120	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	88	-	
<b>Guaranteed Avalanche Characteristics</b>						
Single Pulse Avalanche Energy (Note 5)	EAS	V <sub>DD</sub> =25V , L=0.1mH , I <sub>AS</sub> =20A	45	-	-	mJ
<b>Diode Characteristics</b>						
Continuous Source Current (Note 1, 6)	I <sub>s</sub>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current	-	-	7.5	A
Pulsed Source Current (Note 2, 6)	I <sub>SM</sub>		-	-	30	A
Diode Forward Voltage (Note 2)	V <sub>SD</sub>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C	-	-	1.2	V

Note 1: The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

Note 2: The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%

Note 3: The EAS data shows Max. rating. The test condition is V<sub>DD</sub>=-25V, V<sub>GS</sub>=-10V, L=0.1mH, I<sub>AS</sub>=-27.2A

Note 4: The power dissipation is limited by 150°C junction temperature

Note 5: The Min. value is 100% EAS tested guarantee.

Note 6: The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

❖ TYPICAL CHARACTERISTICS

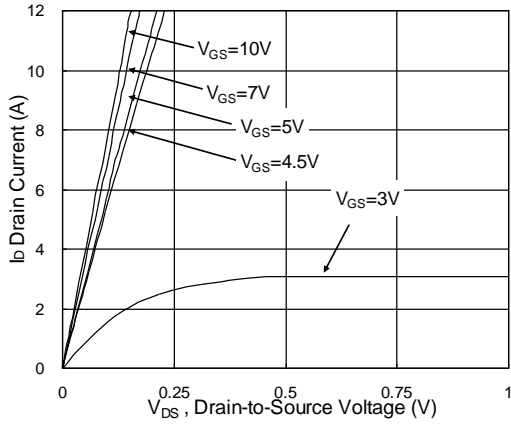


Fig.1 Typical Output Characteristics

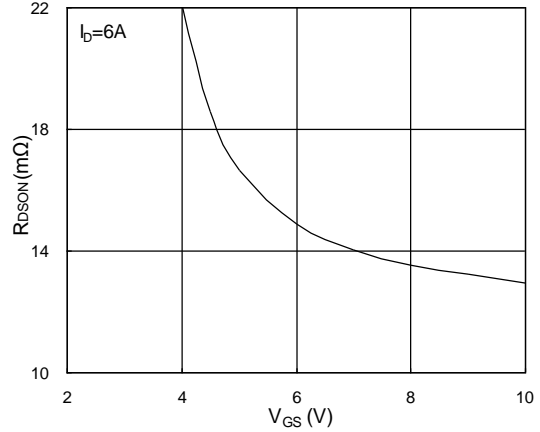


Fig.2 On-Resistance vs. G-S Voltage

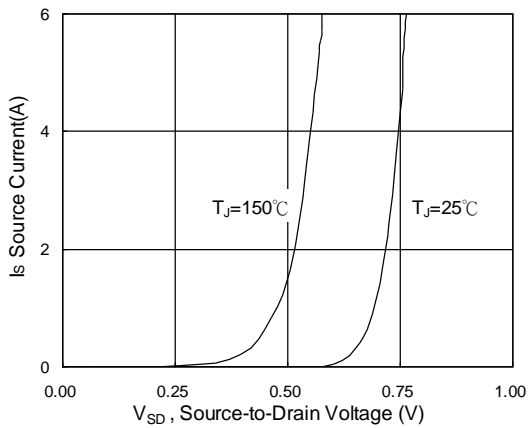


Fig.3 Forward Characteristics of Reverse

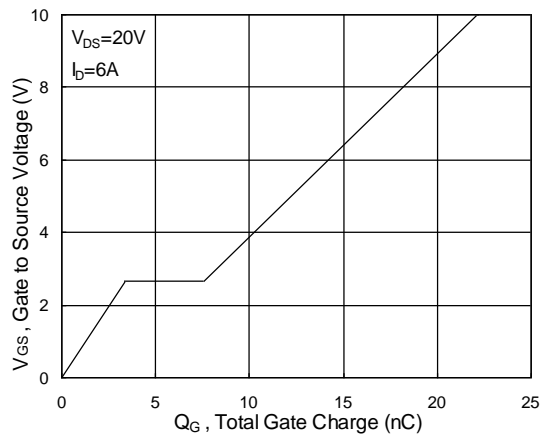


Fig.4 Gate-Charge Characteristics

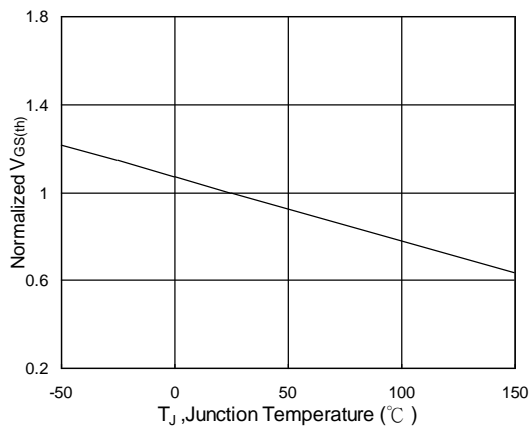


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$

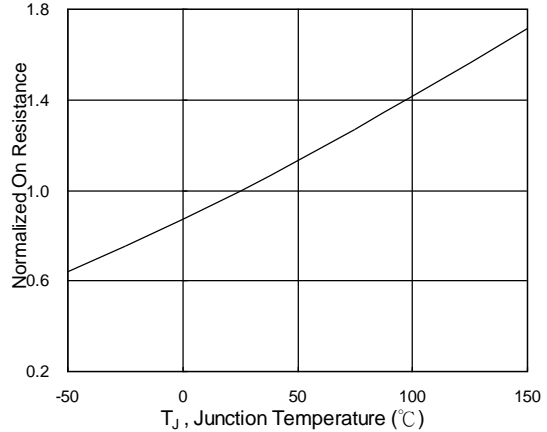


Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$

❖ **TYPICAL CHARACTERISTICS (COUNTINOUS)**

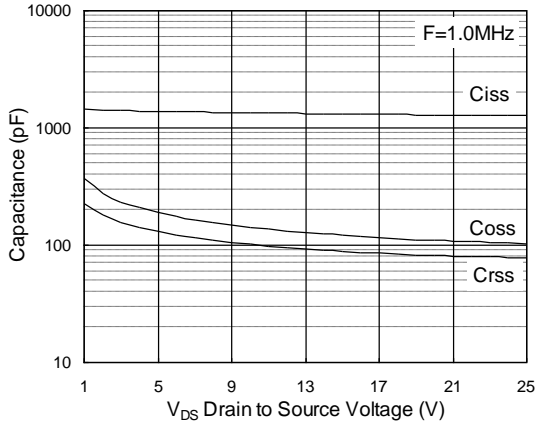


Fig.7 Capacitance

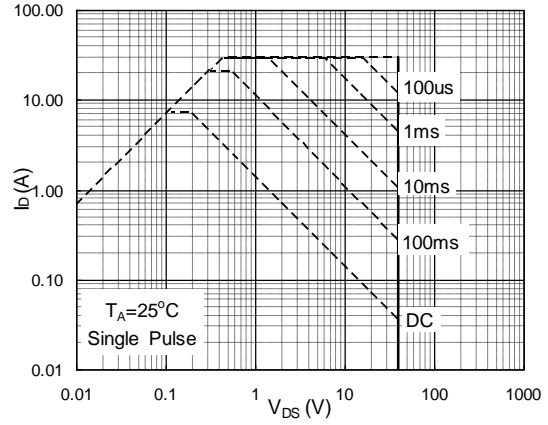


Fig.8 Safe Operating Area

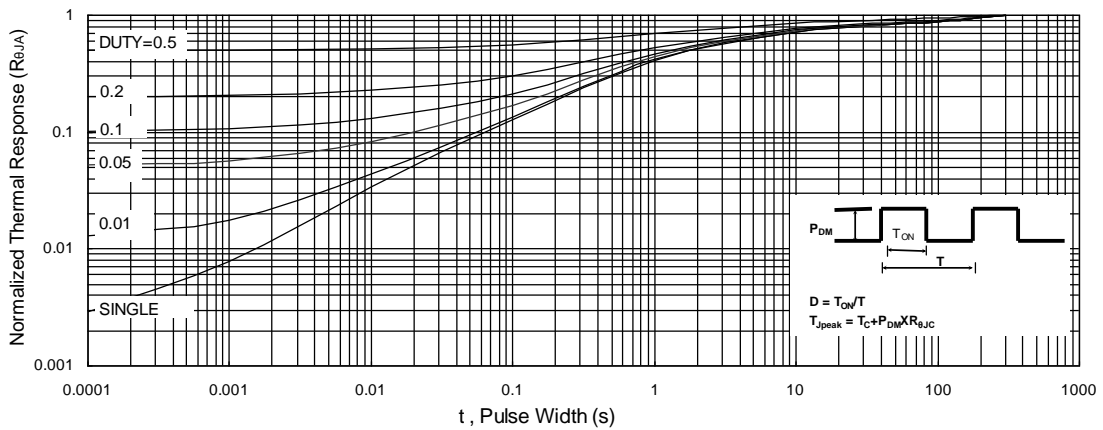


Fig.9 Normalized Maximum Transient Thermal Impedance

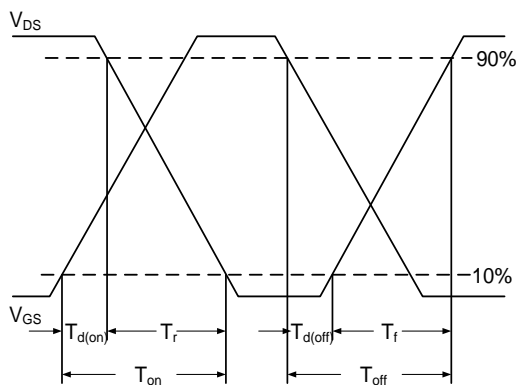


Fig.10 Switching Time Waveform

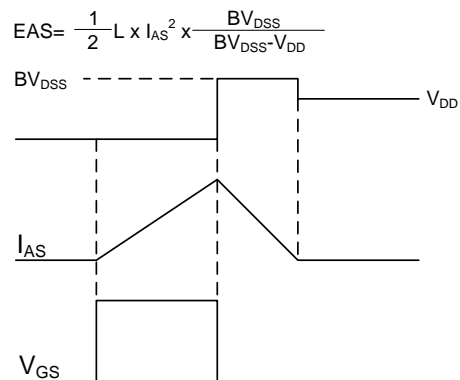


Fig.11 Unclamped Inductive Switching Waveform